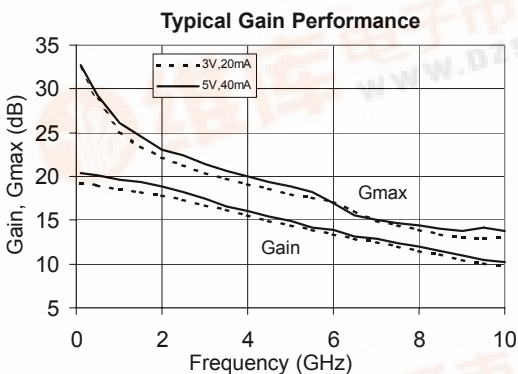




Product Description

Stanford Microdevices' SPF-3043 is a high performance 0.25µm pHEMT Gallium Arsenide FET. This 300µm device is ideally biased at 3V,20mA for lowest noise performance and battery powered requirements. At 5V,40mA the device delivers excellent OIP3 of 32dBm. It provides ideal performance as a driver stage in many commercial and industrial LNA applications.



Preliminary

SPF-3043

Low Noise pHEMT GaAs FET

Qualification Pending April 2001



Product Features

- DC-10 GHz Operation
- Ultra Low NF:
 - 0.25 dB @ 1 GHz
 - 0.50 dB @ 2 GHz
- High Assoc. Gain:
 - 25 dB @ 1 GHz
 - 22 dB @ 2 GHz
- Low Current Draw for NFopt (3V,20mA)
- +32 dBm OIP3, +20 dBm P1dB (5V,40mA)
- Low Cost High Performance pHEMT

Applications

- LNA for Wireless Infrastructure
- Fixed Wireless Infrastructure
- Wireless Data
- Driver Stage for Low Power Applications

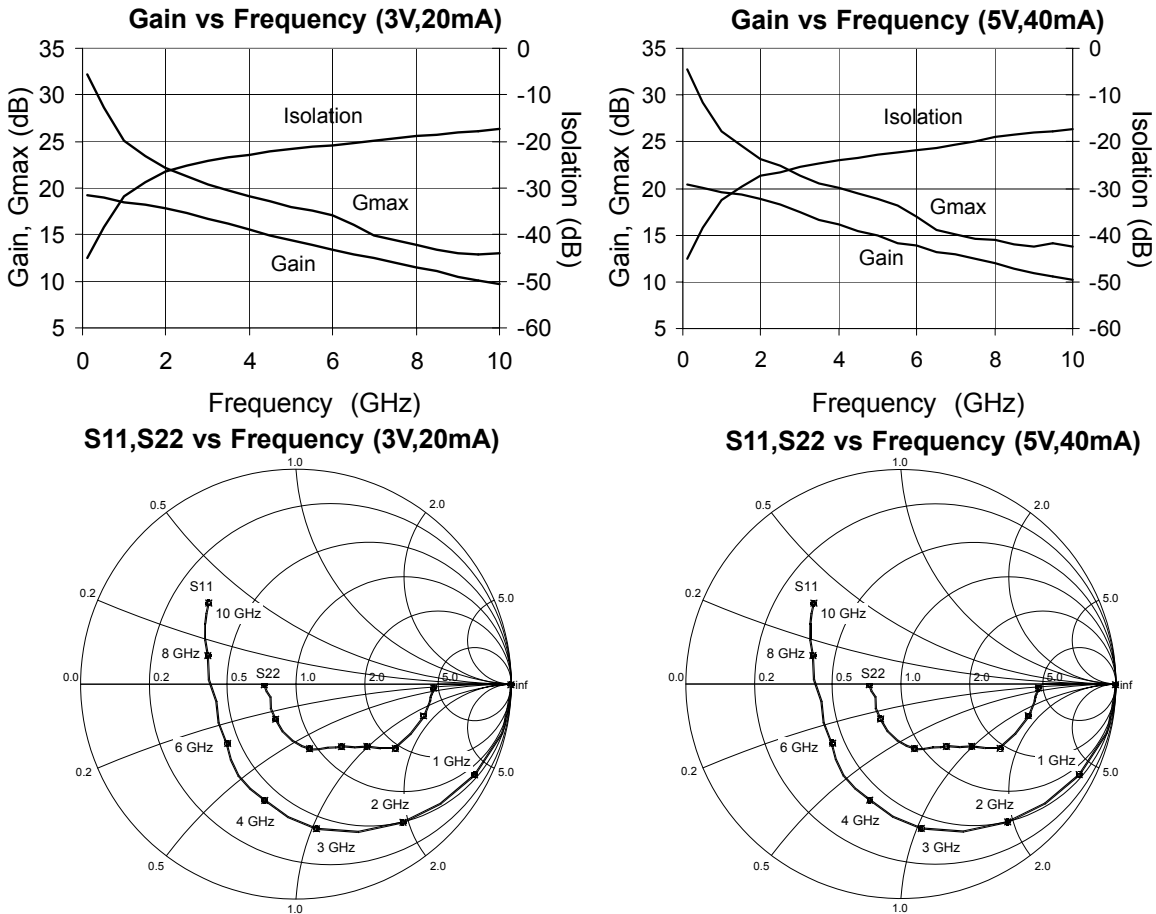
Symbol	Device Characteristics, T = 25°C V _{DS} =3V, I _{DS} =20mA (unless otherwise noted)	Units	Min.	Typ.	Max.
G _{MAX}	Maximum Available Gain Z _S =Z _S [*] , Z _L =Z _L [*]	f = 0.9 GHz f = 1.9 GHz		25.5 22.4	
S ₂₁	Insertion Gain Z _S =Z _L =50Ω	f = 0.9 GHz f = 1.9 GHz		18.5 18.0	
NF _{min}	Minimum Noise Figure Z _S =Γ _{OPT} [*] , Z _L =Z _L [*]	f = 0.9 GHz f = 1.9 GHz		0.25 0.50	
P1dB	Output 1 dB compression point Z _S =Z _S ^{OPT} , Z _L =Z _L ^{LOPT}	V _{DS} =3V, I _{DS} =20 mA V _{DS} =5V, I _{DS} =40 mA		15.5 20	
OIP ₃	Output Third Order Intercept Point Z _S =Z _S ^{OPT} , Z _L =Z _L ^{LOPT}	V _{DS} =3V, I _{DS} =20 mA V _{DS} =5V, I _{DS} =40 mA		29 32	
V _p	Pinchoff Voltage	V _{DS} = 2V, I _{DS} = 0.1 mA	-1.1	-0.8	-0.5
I _{DSS}	Saturated Drain Current	V _{DS} = 2V, V _{GS} = 0V	45	67.5	100
g _{mp}	Peak Transconductance	V _{DS} = 2V, V _{GS} @ g _{mp}	100	150	
BV _{GSO}	Gate-to-Source Breakdown Voltage	I _G = 0.03 mA Drain Open, Source Grounded		-10	-8
BV _{GDO}	Gate-to-Drain Breakdown Voltage	I _G = 0.03 mA Source Open, Drain Grounded		-10	-8
θ _{JA}	Thermal Resistance (junction to lead)			150	

The information provided herein is believed to be reliable at press time. Stanford Microdevices assumes no responsibility for inaccuracies or omissions. Stanford Microdevices assumes no responsibility for the use of this information, and all such information shall be entirely at the user's own risk. Prices and specifications are subject to change without notice. All product data are subject to change without notice. Stanford Microdevices reserves the right to change specifications without notice.



Preliminary
SPF-3043 Low Noise pHEMT GaAs FET

Typical Performance



Note: S-parameters are de-embedded to the device leads with $Z_s = Z_L = 50\Omega$. The data represents typical performance of the device. De-embedded s-parameters can be downloaded from our website (www.stanfordmicro.com).

Typical Performance

Freq (MHz)	V_{DS} (V)	I_{DS} (mA)	Fmin (dB)	Γ_{OPT} Mag \angle Ang	r_N	Gmax (dB)	P1dB (dBm)	OIP3 (dBm)
900	3	20	0.25	0.79 \angle 12	0.22	25.5	15.5	29
	5	40	0.32	0.75 \angle 12	0.25	26.5	20.0	32
1900	3	20	0.50	0.62 \angle 34	0.19	22.4	15.5	29
	5	40	0.54	0.62 \angle 33	0.20	23.3	20.0	32



Preliminary

SPF-3043 Low Noise pHEMT GaAs FET

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Current	I_{DS}	150	mA
Forward Gate Current	I_{GS}	2	mA
Drain-to-Source Voltage	V_{DS}	7	V
Gate-to-Source Voltage	V_{GS}	-3	V
RF Input Power	P_{IN}	15	dBm
Operating Temperature	T_{OP}	-40 to +85	C
Storage Temperature Range	T_{STOR}	-40 to +150	C
Power Dissipation	P_{DISS}	430	mW
Operating Junction Temperature	T_J	+150	C

Part Number Ordering Information

Part Number	Reel Size	Devices/Reel
SPF-3043	7"	3000

Part Symbolization

The part will be symbolized with an "F3" and a Pin 1 indicator on the top surface of the package.

Pin Description

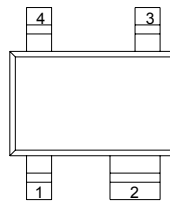
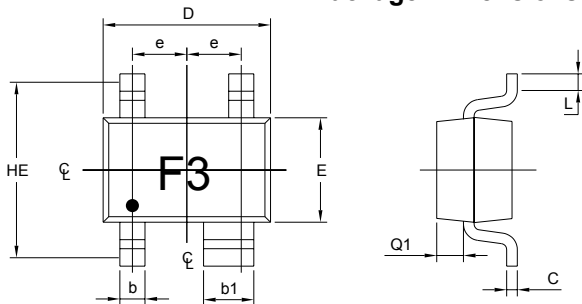
Pin #	Function	Description
1	Gate	RF Input
2	GND & Source	Connection to ground. Use via holes to reduce lead inductance. Place vias as close to ground leads as possible.
3	Drain	RF Output
4	GND & Source	Same as Pin 2



Caution: ESD sensitive

Appropriate precautions in handling, packaging and testing devices must be observed.

Package Dimensions



SYMBOL	MIN	MAX
E	1.15	1.35
D	1.85	2.25
HE	1.80	2.40
A	0.80	1.10
A2	0.80	1.00
A1	0.00	0.10
Q1	0.10	0.40
e	0.65 BSC	
b	0.25	0.40
b1	0.55	0.70
c	0.10	0.18
L	0.10	0.30

NOTE:

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONS ARE INCLUSIVE OF PLATING.
3. DIMENSIONS ARE EXCLUSIVE OF MOLD FLASH & METAL BURR.
4. ALL SPECIFICATIONS COMPLY TO EIAJ SC70.
5. DIE IS FACING UP FOR MOLD AND FACING DOWN FOR TRIM/FORM, i.e.:REVERSE TRIM/FORM.
6. PACKAGE SURFACE TO BE MIRROR FINISH.

Use multiple plated-through vias holes located close to the package pins to ensure a good RF ground connection to a continuous groundplane on the backside of the board.